EMC TEST REPORT

Authorized under Declaration of Conformity

according to

EN 55022 : 1998/ A1:2000 (Class B) EN 55024 : 1998

EN 61000-3-2 : 1995/ A1/ A2:1998/ A14:2000 IEC 61000-4-2 : 1995/ A1:1998/ A2:2000

EN 61000-3-3 : 1995/ A1:1998 IEC 61000-4-3 : 1996/ A1:1998/ A2:2000

IEC 61000-4-4 : 1995/ A2:2000 IEC 61000-4-5 : 1995/ A2:2000 IEC 61000-4-6 : 1996/ A2:2000 IEC 61000-4-11 : 1994/ A2:2000

Issued date: Feb. 05, 2004 1 of 51

Applicant TRENDware International, Inc.

Address 3135 Kashiwa Street, Torrance, CA90505 U.S.A.

Equipment 4-Port ADSL Modem Firewall Router

Model No. TW100-BRM504

Trade Name TRENDware

- The test result refers exclusively to the test presented test model / sample.
- Without written approval of Exclusive Certification Corp. the test report shall not be reproduced except in full.

Contents

CE	RIFICATE	OF COMPLIANCE	4
Def	inition		5
1.	Test of Co	onducted Emission	6
	1.1.	Test Procedures	6
	1.2.	Typical Test Setup Layout of Conducted Emission	7
	1.3.	Conducted Emission Requirement	7
2.	Test of Ra	adiated Emission	8
	2.1.	Test Procedures	8
	2.2.	Typical Test Setup Layout of Radiated Emission	9
	2.3.	Radiated Emission Requirement	9
	2.4.	Test Procedures	9
3.	Harmonio	s Test	10
4.	Voltage F	luctuations Test	11
	4.1.	STANDARD	11
	4.2.	Test Procedure	11
5.	Test setu	o (ESD)	12
	5.1.	Test Setup for Tests Performed in Laboratory	
	5.2.	Test Procedure	13
	5.3.	Test Severity Levels	14
6.	Test Proc	edure (RS)	15
	6.1.	Test Severity Levels	15
7.	Test on P	ower Line (EFT)	16
	7.1.	Test on Communication Lines	16
	7.2.	Test Procedure	16
	7.3.	Test Severity Levels	
8.	Test Proc	edure (Surge)	18
	8.1.	Test Severity Levels	19
9.	Test Proc	edure (CS)	
	9.1.	Test Severity Levels	
10.	Testing R	equirement and Procedure (DIP)	
	10.1.	Test Conditions	
	10.2.	Operating Condition	22
11.	Notice for	· Class A Product	23
12.		on of Conformity and the CE Mark	
13.	Test Conf	iguration of Equipment under Test	24
	13.1.	Test Mode	24
	13.2.	Description of Test System	24
	13.3.	Test Software	24
14.	Feature of	f Equipment under Test	
	14.1.	History of this test report	25
15.		nformation of Test	
16.	Test Data	and Result	
	16.1.	Test Result of Conducted Emission	
	16.2.	Test Result of Radiated Emission	
	16.3.	Harmonics Test	34

Issued date: Feb. 05, 2004 3 of 51

16.4.	Voltage Fluctuations and Flicker Test	35
16.5.	Electrostatic Discharge Immunity Test (ESD)	37
16.6.	Radio Frequency Electromagnetic Field Immunity Test (RS)	40
16.7.	Electrical Fast Transient/Burst Immunity Test (EFT/BURST)	42
16.8.	Surge Immunity Test	44
16.9.	Conducted Disturbances Induced by Radio-Frequency Field Immunity Test (CS)	46
16.10.	Voltage Dips and Voltage Interruptions Immunity Tests	49
16.11.	List of Measuring Equipment Used	51
Appendix	A. Photographs of EUT	. A1~ A6

CERTIFICATE OF COMPLIANCE

according to

EN 55022 : 1998/ A1:2000 (Class B) EN 55024 : 1998

EN 61000-3-2: 1995/ A1/ A2:1998/ A14:2000 IEC 61000-4-2: 1995/ A1:1998/ A2:2000

EN 61000-3-3 : 1995/ A1:1998 IEC 61000-4-3 : 1996/ A1:1998/ A2:2000

IEC 61000-4-4: 1995/ A2:2000 IEC 61000-4-5: 1995/ A2:2000 IEC 61000-4-6: 1996/ A2:2000 IEC 61000-4-11: 1994/ A2:2000

Applicant TRENDware International, Inc.

Address 3135 Kashiwa Street, Torrance, CA90505 U.S.A.

Equipment 4-Port ADSL Modem Firewall Router

Model No. TW100-BRM504

I HEREBY CERTIFY THAT:

The measurements shown in this test report were made in accordance with the procedures given in EUROPEAN COUNCIL DIRECTIVE 89/336/EEC. The equipment was *passed* the test performed according to European Standard EN 55022:1998/ A1:2000 (Class B), EN 61000-3-2:1995/ A1/ A2:1998/ A14:2000, EN 61000-3-3:1995/ A1:1998 and EN 55024:1998 (IEC 61000-4-2 : 1995/ A1:1998/ A2:2000, IEC 61000-4-3 : 1996/ A1:1998/ A2:2000, IEC 61000-4-4 : 1995/ A2:2000, IEC 61000-4-5 : 1995/ A2:2000, IEC 61000-4-11 : 1994/ A2:2000).

The test was carried out on Oct. 23, 2003 at Electronics Testing Center, Taiwan.

Signature
Anson Chou / Manager

Issued date: Feb. 05, 2004 5 of 51

Definition

Unintentional radiator:

A device that intentionally generates and radio frequency energy for use within the device, or that sends radio frequency signals by conduction to associated equipment via connecting wiring, but which is not intended to emit RF energy by radiation or induction.

Class A Digital Device:

A digital device Which is marketed for use in commercial or business environment; exclusive of a device which is market for use by the general public, or which is intended to be used in the home.

Class B Digital Device:

A digital device which is marketed for use in a residential environment notwithstanding use in a commercial, business of industrial environment. Example of such devices that are marketed for the general public.

Note:

A manufacturer may also qualify a device intended to be marketed in a commercial, business, or industrial environment as a Class B digital device, and in fact is encouraged to do so, In the event that a particular type of device has been found to repeatedly cause harmful interference to radio communications, the Commission may classify such a digital device as a Class B Digital Device, Regardless of its intended use.

Intentional radiator:

A device that intentionally generates and emits radio frequency energy by radiation or induction.

Issued date: Feb. 05, 2004 6 of 51

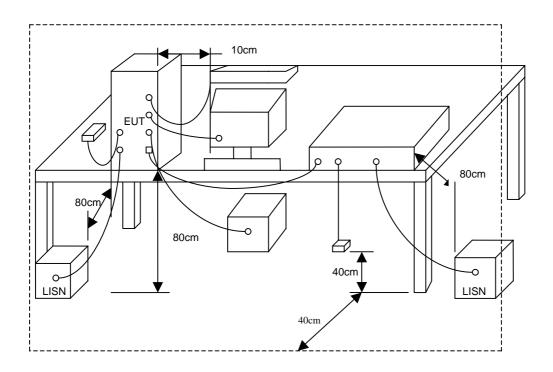
1. Test of Conducted Emission

Conducted Emissions were measured from 150 kHz to 30 MHz with a bandwidth of 9 kHz and return leads of the EUT according to the methods defined in European Standard EN 55022 Clause 9. The EUT was placed on a nonmetallic stand in a shielded room 0.8 meters above the ground plane as shown in section 2.2. The interface cables and equipment positioning were varied within limits of reasonable applications to determine the position producing maximum conducted emissions.

1.1. Test Procedures

- a. The EUT was placed on a desk 0.8 meters height from the metal ground plane and 0.4 meter from the conducting wall of the shielding room and it was kept at least 0.8 meters from any other grounded conducting surface.
- b. Connect EUT to the power mains through a line impedance stabilization network (LISN).
- c. All the support units are connecting to the other LISN.
- d. The LISN provides 50 ohm coupling impedance for the measuring instrument.
- e. The CISPR states that a 50 ohm, 50 microhenry LISN should be used.
- f. Both sides of AC line were checked for maximum conducted interference.
- g. The frequency range from 150 kHz to 30 MHz was searched
- h. Set the test-receiver system to Peak Detect Function and Specified Bandwidth with Maximum Hold Mode.

1.2. Typical Test Setup Layout of Conducted Emission



1.3. Conducted Emission Requirement

The equipment under test EUT shall meet the limits in table 1 and 3 or 2 and 4, as applicable, including the average limit and the quasi-peak limit when using, repectively, an average detector receiver and quasi-peak detector receiver and measured in accordance with the methods described in clause 9. Either the voltage limits or the current limits in table 3 or 4, as applicable, shall be met except for the measurement method of C.1.3 where both limits shall be met. If the average limit is met when using a quasi-peak decetor receiver, the EUT shall be deemeed to meet both limits and measurement with the average detector receiver is unnecessary.

If the reading of the measuring receiver shows fluctuations close to the limit, the reading shall be observed for at least 15 s at each measurement frequency, the higher reading shall be recorded with the exception of any brief isolated hith reading which shall be ignored.

Frequency range	Limits (dB μ V)	
(MHz)	Quasi Peak	Average
0.15 to0.50	66 to 56*	56 to 46*
0.50 to5	56	46
5. to 30.	60	50

NOTE 1-The lower limits shall apply at the transition frequencies.

NOTE 2-The limit decreases linearly with the logarithm of the frequency in the range 0.15 MHZ to 0.50MHZ.

Issued date: Feb. 05, 2004 8 of 51

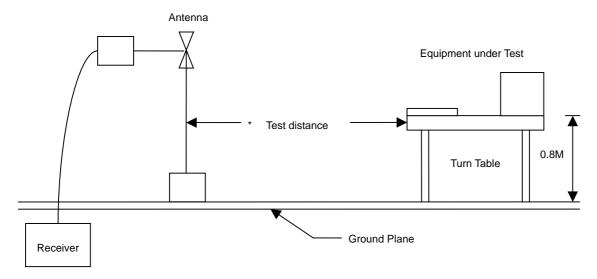
2. Test of Radiated Emission

Radiated emissions from 30 MHz to 1000 MHz were measured with a bandwidth of 120 kHz according to the methods defines in European Standard EN 55022, Clause 10. The EUT was placed on a nonmetallic stand in the open-field site, 0.8 meter above the ground plane, as shown in section 3.2. The interface cables and equipment positions were varied within limits of reasonable applications to determine the positions producing maximum radiated emissions.

2.1. Test Procedures

- a. The EUT was placed on a rotatable table top 0.8 meter above ground.
- b. The EUT was set 10 meters from the interference receiving antenna which was mounted on the top of a variable height antenna tower.
- c. The table was rotated 360 degrees to determine the position of the highest radiation.
- d. The antenna is a half wave dipole and its height is varied between one meter and four meters above ground to find the maximum value of the field strength both horizontal polarization and vertical polarization of the antenna are set to make the measurement.
- e. For each suspected emission the EUT was arranged to its worst case and then tune the antenna tower (from 1 M to 4 M) and turn table (from 0 degree to 360 degrees) to find the maximum reading.
- f. Set the test-receiver system to Peak Detect Function and specified bandwidth with Maximum Hold Mode.
- g. If the emission level of the EUT in peak mode was 3 dB lower than the limit specified, then testing will be stopped and peak values of EUT will be reported, otherwise, the emissions which do not have 3 dB margin will be repeated one by one using the quasi-peak method and reported.

2.2. Typical Test Setup Layout of Radiated Emission



2.3. Radiated Emission Requirement

The EUT shall meet limits of tables as below when measured at the measuring distance R in accordance with the methods described in clause 10. If the reading on the measuring receiver shows fluctuations close to the limit, the reading shall be observed for at least 15 s at each isolated high reading, which shall be ignored.

Limit for radiated disturbance of class B ITE at a measuring distance of 10 m

Frequency	Quasi-peak limits
(MHz)	dB (uV/m)
30 to 230	30
230 to 1000	37

Note 1- The lower limit shall apply at the transition frequency.

2- Additional provisions may be required for cases where interference occurs.

2.4. Test Procedures

The equipment shall be tested under the conditions of Clause 5.

The total impedance of the test circuit, excluding the appliance under test, but including the internal impedance of the supply source, shall be equal to the reference impedance. The stability and tolerance of the reference impedance shall be adequate to ensure that the overall accuracy of $\pm 8\%$ is achieved during the whole assessment procedure.

Issued date: Feb. 05, 2004 10 of 51

3. Harmonics Test

As specified on clause 7 and figure Z1 of EN 61000-3-2:2000, the limits are not specified for equipment with a rated power of 75W or less.

The EUT meets the above condition, so it conforms to EN 61000-3-2.

Issued date: Feb. 05, 2004 11 of 51

4. Voltage Fluctuations Test

4.1. STANDARD

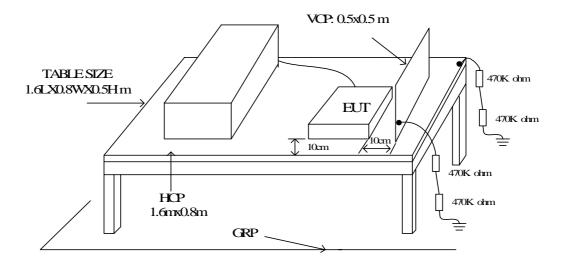
Product Standard: EN 61000-3-3:1995/A1:2001

4.2. Test Procedure

The equipment shall be tested under the conditions of Clause 5.

The total impedance of the test circuit, excluding the appliance under test, but including the internal impedance of the supply source, shall be equal to the reference impedance. The stability and tolerance of the reference impedance shall be adequate to ensure that the overall accuracy of $\pm 8\%$ is achieved during the whole assessment procedure.

5. Test setup (ESD)



The test setup consists of the test generator, EUT and auxiliary instrumentation necessary to perform DIRECT and INDIRECT application of discharges to the EUT as applicable, in the follow manner:

- a. CONTACT DISCHARGE to the conductive surfaces and to coupling plane;
- b. AIR DISCHARGE at insulating surfaces.

The preferred test method is that of type tests performed in laboratories and the only accepted method of demonstrating conformance with this standard. The EUT was arranged as closely as possible to arrangement in final installed conditions.

5.1. Test Setup for Tests Performed in Laboratory

A ground reference plane was provided on the floor of the test site. It was a metallic sheet (copper or aluminum) of 0.25 mm, minimum thickness; other metallic may be used but they shall have at least 0.65 mm thickness. In the Electronics Testing Center, Taiwan, we provided 1 mm thickness stainless steel ground reference plane. The minimum size of the ground reference plane is 2.5 m x 2.5 m, the exact size depending on the dimensions of the EUT. It was connected to the protective grounding system.

The EUT was arranged and connected according to its functional requirements. A distance of 1m minimum was provided between the EUT and the wall of the lab. and any other metallic structure. In cases where this length exceeds the length necessary to apply the discharges to the selected points, the excess length shall, where possible, be placed non-inductively off the ground reference plane and shall not come closer than 0.2m to other conductive parts in the test setup.

Where the EUT is installed on a metal table, the table was connected to the reference plane via a cable with a 470k ohm resister located at each end, to prevent a build-up of charge. The test setup was consist a wooden table, 0.8m high, standing on the ground reference plane. A HCP, 1.6 m x 0.8 m, was placed on the table. The EUT and cables was isolated from the HCP by an insulating support 0.5 mm thick. The VCP size, 0.5 m x 0.5 m.

5.2. Test Procedure

- a. In the case of air discharge testing the climatic conditions shall be within the following ranges:
 - ambient temperature: 15 to 35;
 - relative humidity: 30 to 60;
 - atmospheric pressure: 68 KPa (680 mbar) to 106 KPa (1060 mbar).
- b. Test programs and software shall be chosen so as to exercise all normal modes of operation of the EUT. The use of special exercising software is encouraged, but permitted only where it can be shown that the EUT is being comprehensively exercised.
- c. The test voltage shall be increased from the minimum to the selected test severity level, in order to determine any threshold of failure. The final severity level should not exceed the product specification value in order to avoid damage to the equipment.
- d. The test shall be performed with both air discharge and contact discharge. On preselected points at least 10 single discharges (in the most sensitive polarity) shall be applied on air discharge. On preselected points at least 25 single discharges (in the most sensitive polarity) shall be applied on contact discharge.
- e. For the time interval between successive single discharges an initial value of one second is recommended. Longer intervals may be necessary to determine whether a system failure has occurred.
- f. In the case of contact discharges, the tip of the discharge electrode shall touch the EUT before the discharge switch is operated.
- g. In the case of painted surface covering a conducting substrate, the following procedure shall be adopted:
 - If the coating is not declared to be an insulating coating by the equipment manufacturer, then the pointed tip of the generator shall penetrate the coating so as to make contact with the conducting substrate.
 - Coating declared as insulating by the manufacturer shall only be submitted to the air discharge.
 - ♦ The contact discharge test shall not be applied to such surfaces.
- h. In the case of air discharges, the round discharge tip of the discharge electrode shall be approached as fast as possible (without causing mechanical damage) to touch the EUT. After each discharge, the ESD generator (discharge electrode) shall be removed from the EUT. The generator is then retriggered for a new single discharge. This procedure shall be repeated until the discharges are completed. In the case of an air discharge test, the discharge switch, which is used for contact discharge, shall be closed.

Issued date: Feb. 05, 2004 14 of 51

5.3. Test Severity Levels

Contact Discharge		Air Discharge		
Level	Level Test Voltage (KV) of		Test Voltage (KV) of	
	Contact discharge		Air Discharge	
1	±2	1	±2	
2	±4	2	±4	
3	±6	3	±8	
4	4 ±8 4 ±15			
X	Specified	Х	Specified	
Remark: "X" is an open level.				

Issued date: Feb. 05, 2004 15 of 51

6. Test Procedure (RS)

- a. The equipment to be tested is placed in the center of the enclosure on a wooden table. The equipment is then connected to power and signal leads according to pertinent installation instructions.
- b. The antenna which is enabling the complete frequency range of 80-1000 MHz is placed 3m away from the equipment. The required field strength is determined by placing the field strength meter(s) on top of or directly alongside the equipment under test and monitoring the field strength meter via a remote field strength indicator outside the enclosure while adjusting the continuous-wave to the applicable antennae.
- c. The test is normally performed with the antenna facing the most sensitive side of the EUT. The polarization of the field generated by the biconical antenna necessitates testing each position twice, once with the antenna positioned vertically and again with the antenna positioned horizontally. The circular polarization of the field from the log-spiral antenna makes a change of position of the antenna unnecessary.
- d. At each of the above conditions, the frequency range is swept 80-1000 MHz, pausing to adjust the R.F. signal level or to switch oscillators and antenna. The rate of sweep is in the order of 1.5*10-3 decades/s. The sensitive frequencies or frequencies of dominant interest may be discretely analyzed.

6.1. Test Severity Levels

Frequency Band : 80-1000 MHz		
Level	Test field strength (V/m)	
1	1	
2	3	
3	10	
X	Specified	
Remark: "X" is an open class.		

7. Test on Power Line (EFT)

- a. The EFT/B-generator was located on the GRP.. The length from the EFT/B-generator to the EUT is not exceeding 1 m.
- b. The EFT/B-generator provides the ability to apply the test voltage in a non-symmetrical condition to the power supply input terminals of the EUT..

7.1. Test on Communication Lines

- a. The coupling clamp is composed of a clamp unit for housing the cable (length more than 3 m), and was placed on the GRP.
- b. The coupling clamp provides the ability of coupling the fast transient/bursts to the cable under test.

7.2. Test Procedure

- a. In order to minimize the effect of environmental parameters on test results, the climatic conditions when test is carrying out shall comply with the following requirements:

 - Atmospheric pressure: 68 Kpa (680 mbar) to 106 Kpa (1060 mbar).
- b. In order to minimize the effect of environmental parameters on test results, the electromagnetic environment of the laboratory shall not influence the test results.
- c. The variety and diversity of equipment and systems to be tested make it difficult to establish general criteria for the evaluation of the effects of fast transients/bursts on equipment and systems.
- d. The test results may be classified on the basic of the operating conditions and the functional specification of the equipment under test, according to the following performance criteria:
 - ♦ Normal performance within the specification limits.
 - ♦ Temporary degradation or loss of function or performance which is self-recoverable.
 - Temporary degradation or loss of function or performance which requires operator intervention or system reset.
 - Degradation or loss of function which is not recoverable due to damage of equipment (components).

Issued date: Feb. 05, 2004 16 of 51

Issued date: Feb. 05, 2004 17 of 51

7.3. Test Severity Levels

The following test severity levels are recommended for the fast transient/burst test :

Open circuit output test voltage ± 10		
Level	On Power Supply	On I/O signal, data and control line
1	0.5 KV	0.25 KV
2	1.0 KV	0.50 KV
3	2.0 KV	1.00 KV
4	4.0 KV	2.00 KV
X	Specified	Specified

Remark: "X" is an open level. The level is subject to negotiation between the user and the manufacturer or is specified by the manufacturer.

8. Test Procedure (Surge)

a. Climatic conditions

The climatic conditions shall comply with the following requirements:

- b. Electromagnetic conditions

the electromagnetic environment of the laboratory shall not influence the test results.

- c. The test shall be performed according the test plan that shall specify the test set-up with
 - generator and other equipment utilized;
 - test level (voltage/current);
 - generator source impedance;

 - number of tests: at least five positive and five negative at the selected points;

 - → inputs and outputs to be tested;
 - → representative operating conditions of the EUT;
 - sequence of application of the surge to the circuit;
 - phase angle in the case of AC. power supply;

AC: neutral earthed,

DC: (+) or (-) earthed to simulated the actual earthing conditions.

- d. If not otherwise specified the surges have to be applied synchronized to the voltage phase at the zero-crossing and the peak value of the AC. voltage wave (positive and negative).
- e. The surges have to be applied line to line and line(s) and earth. When testing line to earth, the test voltage has to be applied successively between each of the lines and earth, if there is no other specification.
- f. The test procedure shall also consider the non-linear current-voltage characteristics of the equipment under test. Therefore the test voltage has to be increased by steps up to the test level specified in the product standard or test plan.
- g. All lower levels including the selected test level shall be satisfied. For testing the secondary protection, the output voltage of the generator shall be increased up to the worst-case voltage breakdown level (let-through level) of the primary protection.
- h. If the actual operating signal sources are not available, that may be simulated. Under no circumstances may the test level exceed the product specification. The test shall be carried out according to a test plan.
- i. To find all critical points of the duty cycle of the equipment, a sufficient number of positive and negative test pulses shall be applied. For acceptance test previously unstressed equipment shall be used to the protection devices shall be replaced.

Issued date: Feb. 05, 2004 18 of 51

Issued date: Feb. 05, 2004 19 of 51

8.1. Test Severity Levels

Level	Open-circuit test voltage, ± 10 , KV	NOTE
1	0.5	
2	1.0	This level can be specified in the
3	2.0	product specification.
4	4.0	
Х	Specified	
Remark: "X" is an open class		

9. Test Procedure (CS)

- a. The EUT shall be operated within its intended climatic conditions. The temperature and relative humidity should be recorded.
- b. This test method test can be performed without using a sell shielded enclosure. This is because the disturbance levels applied and the geometry of the setups are not likely to radiated a high amount of energy, especially at the lower frequencies. If under certain circumstances the radiated energy is too high, a shielded enclosure has to be used.
- c. The test shall be performed with the test generator connected to each of the coupling and decoupling devices in turn while the other non-excited RF-input ports of the coupling devices are terminated by a 50 ohm load resistor.
- d. The frequency range is swept from 150 KHz to 230 MHz, using the signal levels established during the setting process, and with the disturbance signal 80% amplitude modulated with a 1KHz sign wave, pausing to adjust the RF-signal level or to switch coupling devices as necessary. The rate of sweep shall no exceed 1.5 x 10⁻³ decades/s. Where the frequency is swept incrementally, the step size shall no exceed 1% of the start and thereafter 1% of the preceding frequency value.
- e. The dwell time at each frequency shall not be less than the time necessary for the EUT to be exercised, and able to respond. Sensitive frequencies e.g. clock frequency (ies) and harmonics or frequencies of dominant interest shall be analyzed separately.
- f. An alternative test procedure may be adopted, wherein the frequency range is swept incrementally, with a step size not exceeding 4% of the start ad thereafter 4% of the preceding frequency value. The test level should be at least twice the value of the specified test level.
- g. In cases of dispute, the test procedure using a step size not exceeding 1% of the start and thereafter 1% of preceding frequency value shall take precedence.
- h. Attempts should be made to fully exercise the EUT during testing, and to fully interrogate all exercise modes selected for susceptibility.
- i. The use of special exercising programs is recommended.
- j. Testing shall be performed according to a Test Plan, which shall be included in the test report.
- k. It may be necessary to carry out some investigatory testing in order to establish some aspects of the test plan.

Issued date: Feb. 05, 2004 21 of 51

9.1. Test Severity Levels

Level	Voltage Level (EMF),
1	1 V
2	3 V
3	10 V
X	Specified

NOTE - x is an open class.

This level can be specified in the product specification.

Issued date: Feb. 05, 2004 22 of 51

10. Testing Requirement and Procedure (DIP)

10.1. Test Conditions

1. Source voltage and frequency: 230V / 50Hz, Single phase.

2. Test of interval: 10 sec.

3. Level and duration: Sequence of 3 dips/interrupts.

4. Voltage rise (and fall) time : 1 \sim 5 $\mu s.$

5. Test severity:

Voltage dips and	Test Duration
Interrupt reduction (%)	(ms)
30	500
60	100
100	10
100	80
100	5000

10.2. Operating Condition

Full system

Issued date: Feb. 05, 2004 23 of 51

11. Notice for Class A Product

This Notice is for class A product only. If the Equipment under Test is a class B product, this notice should be disregarded.

Class A ITE is a category of all other ITE which satisfies the class A ITE limits but not the class B ITE limits. Such equipment should not be restricted in its sale but the following warning shall be included in the instructions for use:

Warning

This is a class A product. In a domestic environment this product may cause radio interference in which case the user may be required to take adequate measures.

12. Declaration of Conformity and the CE Mark

There are three possible procedures pertaining to the declaration of conformity:

- 12.1. Conformity Testing and Declaration of Conformity by the Manufacturer or His Authorized Representative Established within the Community or by an Importer.
 - Article 10 (1) of the EMC Directive, § 3 (1) no. 2a of the EMC Act.
- 12.2. Declaration of Conformity Issued by the Manufacturer or His Authorized Representative Established within the Community or by an Importer Following Testing of the Product and Issued of an EC certificate of conformity by a competent body.
 - Article 10 (2) of the EMC Directive, § 3 (1) no. 2b of the EMC Act.
- 12.3. Declaration of Conformity Issued by the Manufacturer or His Authorized Representative Established within the Community or by an Importer Following Testing and Certification of the Product by a Notified Body.
 - Article 10 (5) of the EMC Directive,
 - § 3 (1) no. 2b of the EMC Act (radio transmitting installations).

12.4. Specimen For The CE Marking Of Electrical / Electronic Equipment

The components of the CE marking shall have substantially the same vertical dimension, which may not be less than 5 mm.



Issued date: Feb. 05, 2004 24 of 51

13. Test Configuration of Equipment under Test

13.1. Test Mode

- The following test mode was performed for conduction test.
- Frequency range investigated: conduction 150 KHz to 30 MHz, radiation 30 MHz to 1000MHz.

13.2. Description of Test System

Support Unit 1. – ADSL Router Manufacturer : Sercomm Model No. : IP505A

Power Cord: Non-Shielded, 1.2m

Support Unit 2. – Notebook PC

Manufacturer : Compaq

Model No. : Presario 2800

Power Cord: Non-Shielded, 1.8m

13.3. Test Software

At the same time, "Ping.EXE" was executed to link with the remote workstation to receive and transmit data by UTP Cable.

Issued date: Feb. 05, 2004 25 of 51

14. Feature of Equipment under Test

- 1. A powerful, true firewall.
- 2. Content filtering.
- 3. Auto Sensing and Auto UplinkTM LAN Ethernet connections.
- 4. Extensive Internet protocol support.
- 5. Easy, Web-based setup for installation and management.
- 6. A built-in ADSL modem.

14.1. History of this test report

The Model No. TW100-BRM504 (Report No:CE04020401-A) is the same and it only differs from the outside cosmetic. The functions and specifications are the same.

Issued date: Feb. 05, 2004 26 of 51

15. General Information of Test

Test Site :	Electronics Testing Center, Taiwan No. 34, Lin 5, Ding Fu Tsun, Linkou Hsiang, Taipei Hsien, Taiwan, R.O.C.
Test Voltage :	AC 230V/ 50Hz
Test in Compliance with:	EMI Test (conduction and radiation) :
	European Standard EN 55022 Class B
	Harmonics Test :
	European Standard EN 61000-3-2.
	Voltage Fluctuations Test :
	European Standard EN 61000-3-3.
	EMS Test :
	European Standard EN 55024.
	ESD : IEC 61000-4-2,
	RS : IEC 61000-4-3,
	EFT : IEC 61000-4-4,
	SURGE : IEC 61000-4-5,
	CS : IEC 61000-4-6,
	Power Frequency Magnetic Field : IEC 61000-4-8,
	DIPS : IEC 61000-4-11

16. Test Data and Result

16.1. Test Result of Conducted Emission

16.1.1 Test Mode: Operation Mode

Relative Humidity : 65 % Relative Humidity : 25°C

Test Date : Sep. 29, 2003

All emissions not reported here are more than 10 dB below the prescribed limit.

The Conducted Emission test was passed at minimum margin NEUTRAL 4.453 MHz / 51.7 dBuV.

Ν

	Meter F	Reading		Result (dBuV)		Limit		Margins		
Freq.	(dB	uV)	V) Factor				(dBuV)		(dB)	
(MHz)	Q.P	AVG.	(dB)	Q.P	AVG.	Q.P	AVG.	Q.P	AVG.	
	Value	Value		Value	Value	Value	Value	Q.P	AVG.	
3.285	40.9		0.6	41.5		56.0	46.0	-14.5		
3.848	40.0		0.6	40.6		56.0	46.0	-15.4		
4.055	48.2	33.6	0.6	48.8	34.2	56.0	46.0	-7.2	-11.8	
4.258	50.4	38.0	0.6	51.0	38.6	56.0	46.0	-5.0	-7.4	
4.453	51.7	39.2	0.6	52.3	39.8	56.0	46.0	-3.7	-6.2	
4.468	48.8	35.9	0.6	49.4	36.5	56.0	46.0	-6.6	-9.5	

L1

Freq.	Meter Reading (dBuV)		Factor	Result (dBuV)		Limit (dBuV)		Margins (dB)	
	(42		1 40.01	1 40101		(abav)		(32)	
(MHz)	Q.P	AVG.	(dB)	Q.P	AVG.	Q.P	AVG.	Q.P	AVG.
	Value	Value		Value	Value	Value	Value	Q.F	AvG.
3.285	33.9		0.6	34.5		56.0	46.0	-21.5	
3.848	33.4		0.6	34.0		56.0	46.0	-22.0	
4.055	42.5		0.6	43.1		56.0	46.0	-12.9	
4.258	44.3		0.6	44.9		56.0	46.0	-11.1	
4.453	45.8	34.8	0.6	46.4	35.4	56.0	46.0	-9.6	-10.6
4.468	43.0		0.6	43.6		56.0	46.0	-12.4	

Notes:

- 1. The EUT was placed 0.8m above reference ground plane.
- 2. Example calculation : result for 3.285 MHz: 40.9 + 0.6 = 41.5 dB μV
- 3. The symbol of "---" means the Q.P. value is under the limit for AVG. so, the AVG.value doesn't need to be measured.

Issued date: Feb. 05, 2004 28 of 51

4. The expanded uncertainty of the conducted emission tests is 2.45 dB.

Issued date: Feb. 05, 2004 29 of 51

CONDUCTION EMISSION TEST

Peak Value

EUT:

IP505A

Manuf: Op Cond: Operator: Test Spec: Comment

Ν

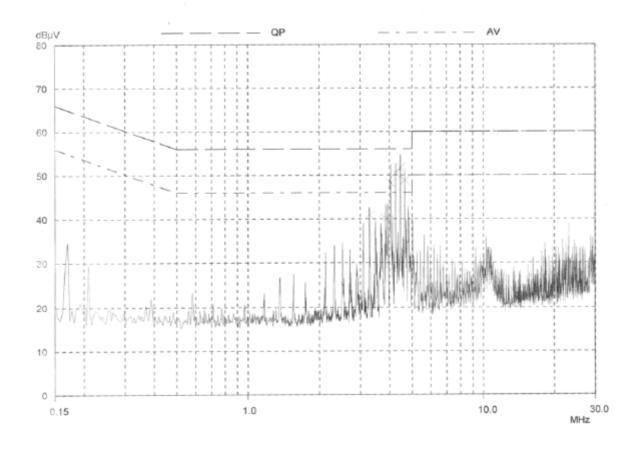
Final Measurement:

Detector: Meas Time:

Peaks:

X QP 1sec

25 dB Acc Margin:



Issued date: Feb. 05, 2004 30 of 51

CONDUCTION EMISSION TEST

Peak Value

EUT: IP505A

Manuf: Op Cond: Operator:

Test Spec:

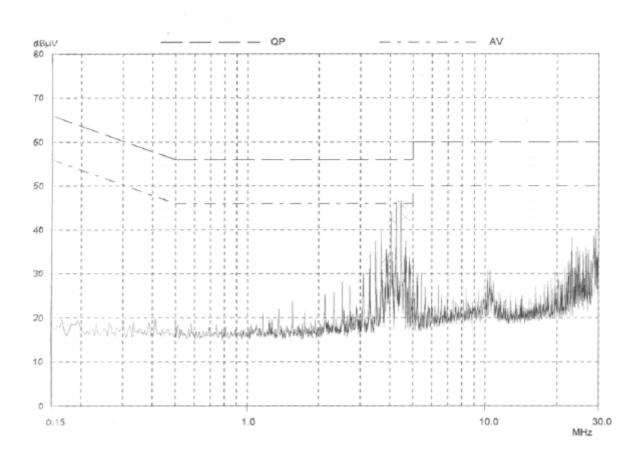
Comment:

Final Measurement:

Detector: Meas Time: Peaks: X QP 1sec

25 dB

Acc Margin:



16.1.2 Photographs of Conducted Emission Test Configuration



FRONT VIEW



REAR VIEW

16.2. Test Result of Radiated Emission

16.2.1 Test Mode: Operation Mode

Relative Humidity : 65 % Temperature : 25°C

Test Date : Sep. 29, 2003

Emission level $(dBuV/m) = 20 \log Emission level (uV/m)$

Corrected Reading : Antenna Factor + Cable Loss + Read Level - Preamp

Factor = Level

HOR.

Emission	Meter Reading	CORR'd	Results	Limit (3m)	Margins
frequency (MHz)	(dBuV)	Factor (dB)	(dBuV/m)	(dBuV/m)	(dB)
42.952	30.9	-15.6	15.3	30	-14.7
200.914	39.4	-13.3	26.0	30	-4.0
250.856	41.4	-9.2	32.2	37	-4.8
231.800	39.0	-10.8	28.2	37	-8.8
377.011	36.3	-6.3	30.0	37	-7.0
500.897	32.8	-4.2	28.6	37	-8.4

VERT.

Emission	Meter Reading	CORR'd	Results	Limit (3m)	Margins
frequency (MHz)	(dBuV)	Factor (dB)	(dBuV/m)	(dBuV/m)	(dB)
42.952	39.4	-15.6	23.8	30	-6.2
200.914	36.3	-13.3	23.0	30	-7.0
250.856	41.0	-9.2	31.8	37	-5.2
231.800	33.9	-10.8	23.1	37	-13.9
377.011	32.9	-6.3	26.6	37	-10.4
500.897	29.7	-4.2	25.5	37	-11.5

Notes:

- 1. Measurement Distance: 10 m
- 2. Height of table on which the EUT was placed: 0.8 m
- 3. Height of Receiving Antenna: 1 4 m
- 4. Example Calculation : result for 42.952 MHz: $30.9 + (-15.6) = 15.3 \text{ dB}\mu\text{V/m}$
- 5. Remark "---" means that the emissions level is too low to be measured.
- 6. The expanded uncertainty of the radiated emission tests is -3.53 dB.

16.2.2 Photographs of Radiated Emission Test Configuration

• The photographs show the configuration that generates the maximum emission.



FRONT VIEW



Issued date: Feb. 05, 2004 33 of 51

REAR VIEW

Issued date: Feb. 05, 2004 34 of 51

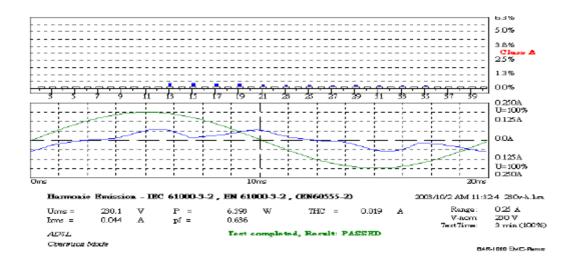
16.3. Harmonics Test

FINAL TEST RESULT : PASS
Fundamental Current : 0.082 A
Real Power : 11.69 W
Power Factor : 0.618
Temperature : 25°C
Relative Humidity : 45%

Test Date : Oct. 02, 2003

Urms = 230.1V Freq = 49.984 Range: 0.25A Irms = 0.044A Ipk = 0.073A cf = 1.682 P = 6.393W Pap = 10.06VA pf = 0.636 THDi = 42.70% THDu = 0.10% Calss A

P = 0.393W	Pap = 10.00	ovA pi = 0	0.030	1 HDI = 42.70% $1 HDII = 0.10%$ Calss A					
Test-Time: 3	3 min (100%)			Test completed Result: PASSED					
Order	Freq. (Hz)	Imax (A)	Limit (A)	Order	Freq. (Hz)	Imax (A)	Limit (A)		
1	50	0.149		21	1050	0.0003	0.1071		
2	100	0.0005	1.08	22	1100	0	0.0836		
3	150	0.0122	2.3	23	1150	0.0002	0.978		
4	200	0.0003	0.43	24	1200	0	0.0767		
5	250	0.0136	1.14	25	1250	0.0002	0.09		
6	300	0.0002	0.3	26	1300	0	0.0708		
7	350	0.0019	0.77	27	1350	0.0001	0.0833		
8	400	0.0001	0.23	28	1400	0	0.0657		
9	450	0.0022	0.4	29	1450	0.0002	0.0776		
10	500	0	0.184	30	1500	0	0.0613		
11	550	0.0016	0.33	31	1550	0.0001	0.0726		
12	600	0	0.1533	32	1600	0	0.0575		
13	650	0.0008	0.21	33	1650	0.0001	0.0682		
14	700	0	0.1314	34	1700	0	0.0541		
15	750	0.0006	0.15	35	1750	0.0001	0.0643		
16	800	0	0.115	36	1800	0	0.0511		
17	850	0.0004	0.1324	37	1850	0.0001	0.0608		
18	900	0	0.1022	38	1900	0	0.0484		
19	950	0.0004	0.1184	39	1950	0.0001	0.0577		
20	1000	0	0.092	40	2000	0	0.046		



16.4. Voltage Fluctuations and Flicker Test

Basic Standard : EN 61000-3-3:1995/A1:1998

FINAL TEST RESULT: PASS Temperature: 25

Test Data : Oct. 02, 2003 Relative Humidity : 45 % RH

	Pst	Plt	Dc (%)	Dmax (%)	Dt (%)
Reading	0.070	0.070	0.00	0.00	0.00
Limit	0.65	1.0	3.0	4.0	3.0

16.4.1 TEST EQUIPMENT SETTINGS

Line Voltage: 230 V
 Test Duration: 00:10:00 minutes

Line Frequency: 50 Hz
 Measurement Delay: 10.0 seconds

Pst Integration Periods: 1
 Pst Integration Time: 10 minutes

16.4.2 Photographs of Harmonics test, Voltage Fluctuation and Flicker test



Harmonics



Issued date: Feb. 05, 2004 36 of 51

Flicker

Issued date: Feb. 05, 2004 37 of 51

16.5. Electrostatic Discharge Immunity Test (ESD)

Final Test Result : PASS

Pass performance Criteria : A

Required performance criteria : B

Basic Standard : IEC 61000-4-2:1995

Product Standard : EN 55024:1998/A1:2001

Level 3 for air discharge,

2 for contact discharge

Test Voltage $\pm 2 / \pm 4 / \pm 8$ KV for air discharge,

±2 / ±4 KV for contact discharge

Temperature : 25 °C

Relative Humidity : 50 %

Atmospheric Pressure : 990 mbar

Test Date : Oct. 08, 2003

16.5.1 Test Record

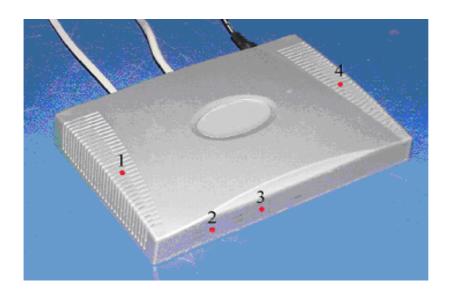
	Contact Discharge: times / each			Air Discharge: 10 times / each								
Voltage	2	ΚV	4	kV		kV	2	kV	4	kV	8	8 kV
Point\Polarity	+		+		+		+		+		+	
HCP	Α	Α	Α	Α								
VCP	Α	Α	Α	Α								
P ₁ ~P ₆							Α	Α	Α	Α	Α	Α
P ₇ ~P ₁₁	В	В	В	В								

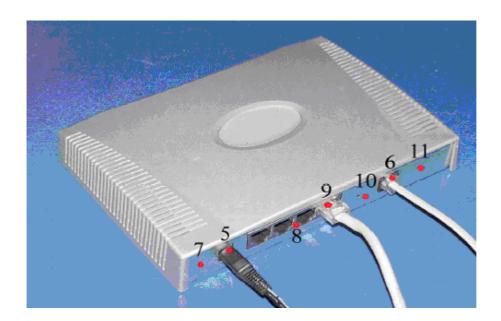
Note: "A" means the EUT function was normal during the test.

[&]quot;B" means the EUT's function was fail during test. After test, the EUT operate as intended without operator intervention.

Issued date: Feb. 05, 2004 38 of 51

16.5.2 TEST POINTS





16.5.3 Photographs of Electrostatic Discharge Immunity Test



16.6. Radio Frequency Electromagnetic Field Immunity Test (RS)

Final Test Result : PASS

Pass performance Criteria : A

Required performance criteria : A

Basic Standard : IEC 61000-4-3:1995

Product Standard : EN 55024:1998/A1:2001

Level : 2

Frequency Range : 80-1000 MHz

Field Strength : 3 V/m (Modulated 80% AM)

Temperature : 26 °C
Relative Humidity : 65 %

Atmospheric Pressure : 990 mbar

Test Date : Oct. 21, 2003

16.6.1 Test Record

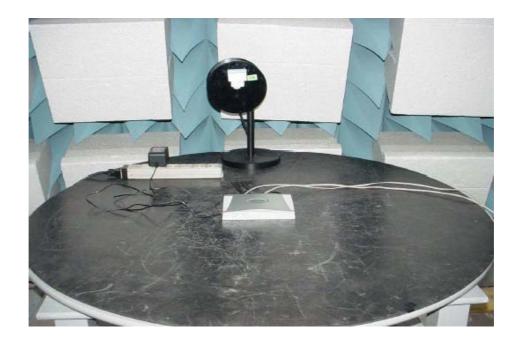
Modulation: AM 80%, 1KHz sine wave, Dell time: 2.9 S

Frequency Step Size: 1 % of preceding frequency value

Frequency	Field strength (V/m)	Polarization of Device	Result
80~1000	3 V/m	Vertical	Α
80~1000	3 V/m	Vertical	А
80~1000	3 V/m	Vertical	Α

Note: "A" means the EUT function was normal during the test.

16.6.2 Photographs of Radio Frequency Electromagnetic Field Immunity Test



16.7. Electrical Fast Transient/Burst Immunity Test (EFT/BURST)

Final Test Result : PASS

Pass performance Criteria : A

Required performance criteria : B

Basic Standard : IEC 61000-4-4:1995

Product Standard : EN 55024:1998/A1:2001

Level : 2

Test Voltage : on Power Supply – 2

on I/O signal, data and control line -- 2

Temperature : 25 °C

Relative Humidity : 45 %

Atmospheric Pressure : 990 mbar

Test Date : Oct. 03, 2003

16.7.1 Test Recode

Pulse : 5/50 ns Repetition Rate: <u>2.5 kHz</u> above 2.0 kV

Burst : 15m/300ms 5 kHz below and equal 2.0Kv

Voltage/ Mode/ Polarity/ Result/ Phase		<u>0.5</u> kV		<u>1</u> kV		
		+	+			
	L	А	А	А	Α	
Power Line	N	А	Α	А	Α	
	L-N	А	А	А	А	
Signal Line (RJ-45)		А	А	А		
Т	el Line (RJ-45)	А	А	А		

Note: "A" Means the EUT function was normal during the test.

16.7.2 Photographs of Electrical Fast Transient/BURST Immunity Test



FRONT VIEW



Issued date: Feb. 05, 2004 43 of 51

REAR VIEW

16.8. Surge Immunity Test

FINAL TEST RESULT : PASS

Pass performance Criteria : A

Required performance criteria: B

Basic Standard : IEC 61000-4-5 (1995)

Product Standard : EN 55024:1998/A1:2001

Surge wave form (Tr/Th) : 1, 2/50 8/20 μ s

on Signal ports And Telecommunication – N/A

on Input AC Power Port -- 2

Test Voltage on Signal ports And Telecommunication – N/A

on Input AC Power Port -- ±1.0 KV

Temperature : 25 °C

Relative Humidity : 45 %

Atmospheric Pressure : 990 mbar

Test Date : Oct. 03, 2003

16.8.1 Test Recode

Waveform : 1.2/50µs(8/20µs) Repetition rate : 60_sec Time : 1_time/each condition							
Voltage	e / Mode / Polarity /	0°	90°	180°	270°	360°	
0.5/ 1.0	L-N	+	Α	Α	Α	Α	Α
kV	L-IN		Α	Α	А	Α	Α
0.5 10/	Tel Line	+	Α	А	Α	Α	Α
<u>0.5</u> kV	iei Lille	_	Α	Α	Α	Α	Α

Note: "A" Means the EUT function was normal during the test.

16.8.2 Photographs of Surge Immunity Test



FRONT VIEW



Issued date: Feb. 05, 2004 45 of 51

REAR VIEW

16.9. Conducted Disturbances Induced by Radio-Frequency Field Immunity Test (CS)

Final Test Result : PASS

Pass performance Criteria : A
Required performance criteria : A

Basic Standard : IEC 61000-4-6 (1996)

Product Standard : EN 55024:1998/A1:2001

Level : 2

Test Voltage : 3 V rms (Modulated, 1KHz, 80%, AM)

Frequency Range : 0.15 MHz to 80 MHz

Test Port : on AC Power

Dwell time : 2.9 seconds

Frequency step size : 1 %

Coupling mode : CDN-M2 for AC power ports, CDN-RJ45 for Signal Ports

Temperature : 23°C

Relative Humidity : 50 %

Atmospheric Pressure : 990 mbar

Test Date : Oct. 23, 2003

16.9.1 Test Recode

Frequency: 0.15~80MHz Modulation: AM 80%,1KHz sine wave Dell time: 2.9s							
Frequency Step Size: 1 % of preceding frequency value							
Frequency Test mode Voltage(V) Result							
0.15 ~ 80MHz	Power Line (M2)	3	А				
0.15 ~ 80MHz	Lan Line	3	А				
0.15 ~ 80MHz	Tel Line	3	А				

Note: "A" Means the EUT function was normal during the test.

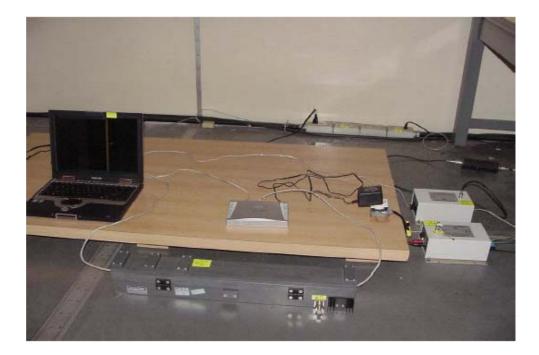
16.9.2 Photographs of CS Tests



POWER LINE



LAN LINE



TEL LINE

16.10. Voltage Dips and Voltage Interruptions Immunity Tests

Final Test Result : PASS

Pass performance Criteria : C for voltage interruption, A for voltage dips

Required performance criteria: C for voltage interruption, B/C for voltage dips

Basic Standard : IEC 61000-4-11 (1994)

Product Standard : EN 55024:1998/A1:2001

Temperature : 25 °C

Relative Humidity : 50 %

Atmospheric Pressure : 990 mbar

Test Date : Oct. 06, 2003

16.10.1 Test Record

Voltage(UT): AC 230 V 50 Hz Interval(s): 10s Times: 12							
	Test level	Durations	Phase / Result				
Test mod	UT %	(period)	0°	180°			
Voltage interruptions	>95%	250	С	С			
	30%	0.5	А	А			
Voltage dips	>95%	25	А	А			

Note: "A" means the EUT function was normal during the test.

Test Engineer:

Tiffany Wu

[&]quot;C" means the EUT's power off during test, and recovered by itself after the test.

Issued date: Feb. 05, 2004 50 of 51

16.10.2 Photographs of Voltage Dips and Voltage Interruptions Immunity Tests



16.11. List of Measuring Equipment Used

<EMI>

Instrument	Manufacturer	Model No.	Calibration Date	Remark
Shielded Room	Riken		N.C.R.	Conduction
EMI test receiver	R&S	ESCS30	Nov. 28, 2002	Conduction
L.I.S.N.	EMCO	ESH2-Z5	Sep. 04, 2003	Conduction
Monitor	IBM	E54	N.C.R.	Conduction
Printer	HP	LaserJet 1000	N.C.R.	Conduction
Computer	Acer	Veriton 7500g	N.C.R.	Conduction
Amplifier Receiver	HP	8447D	Feb. 20, 2003	Radiation
Bilog Antenna	Chase	CBL6111C	Nov. 05, 2002	Radiation
Pre -selector	HP	85685A	Jan. 09, 2003	Radiation
Spectrum Analyzer	HP	8568B	Jan. 09, 2003	Radiation
Quasi-Peak Adaptor	HP	85650A	Jan. 09, 2003	Radiation

^{*}Calibration Interval of instruments listed above is one year.

< EMS>

Instrument	Manufacturer	Model No.	Calibration Date	Remark
EMC Immunitytester	EMC-Partener	TRANSIENT-1000	2003/8/18	ESD
Metering Unit & Probe	EMCO	7122	2003/7/15	RS
SMGL Generator	R&S	1020.2005.52	2003/12/24	RS
Amplifier	IFI	M5540	2003/12/10	RS
GTEM CELL	EMCO	5317	2003/7/10	RS
Data Processing	EMCO	7110	N.C.R.	RS
EMC Immunitytester	EMC-Partener	TRANSIENT-1000	2003/8/19	Surge/ EFT/DIP
Test System	FRANKONIA EMV-Mess-System GmbH	CIT-10	2003/7/23	CS
CDN	FRANKONIA EMV-Mess-System GmbH	CDN M2+M3	2003/7/17	CS
CDN	FRANKONIA EMV-MESS-SYSTEM GmbH	CDN RJ11	2003/7/17	CS
EM Injection Clamp	SCHAFFNER	KEMZ801	2003/8/22	cs